

# e-Diagnostics/EEC Workshop Closing Remarks

[www.sematech.org/public/resources/ediag/index.htm](http://www.sematech.org/public/resources/ediag/index.htm)

Harvey Wohlwend / International SEMATECH

harvey.wohlwend@sematech.org,

512.356.7536

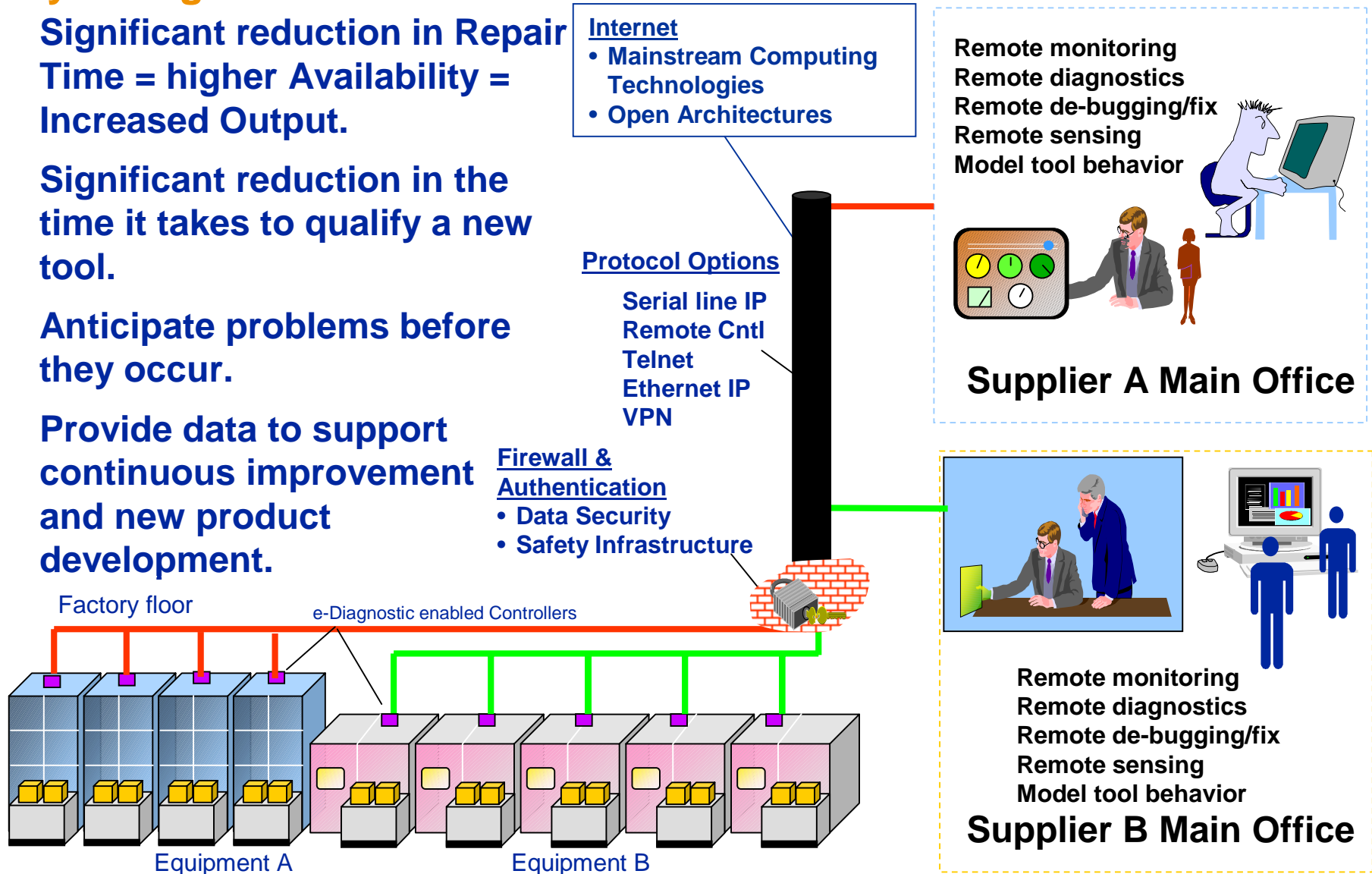
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INTERNATIONAL  
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# e-Diagnostics Vision

## Why e-Diagnostics?

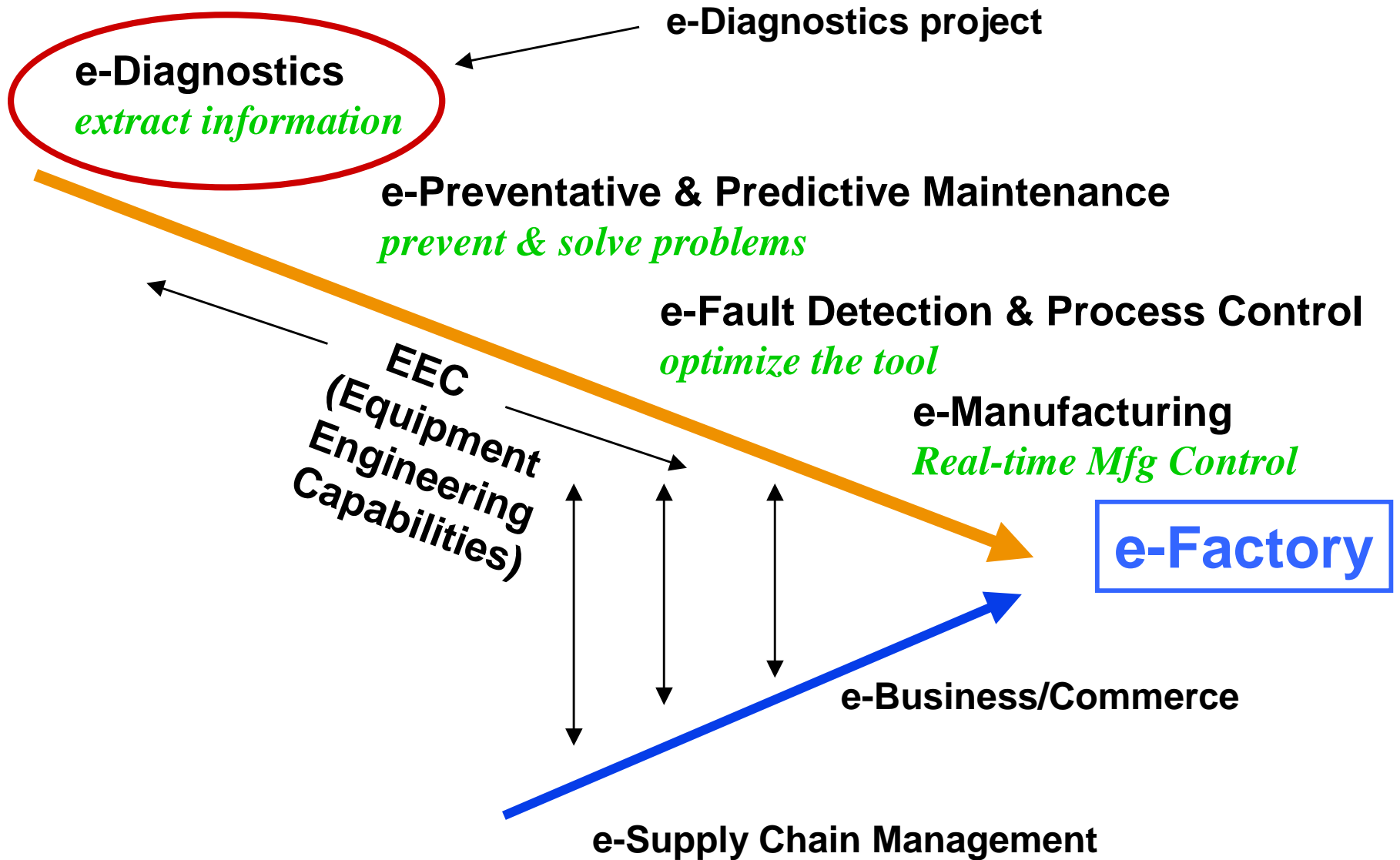
- Significant reduction in Repair Time = higher Availability = Increased Output.
- Significant reduction in the time it takes to qualify a new tool.
- Anticipate problems before they occur.
- Provide data to support continuous improvement and new product development.



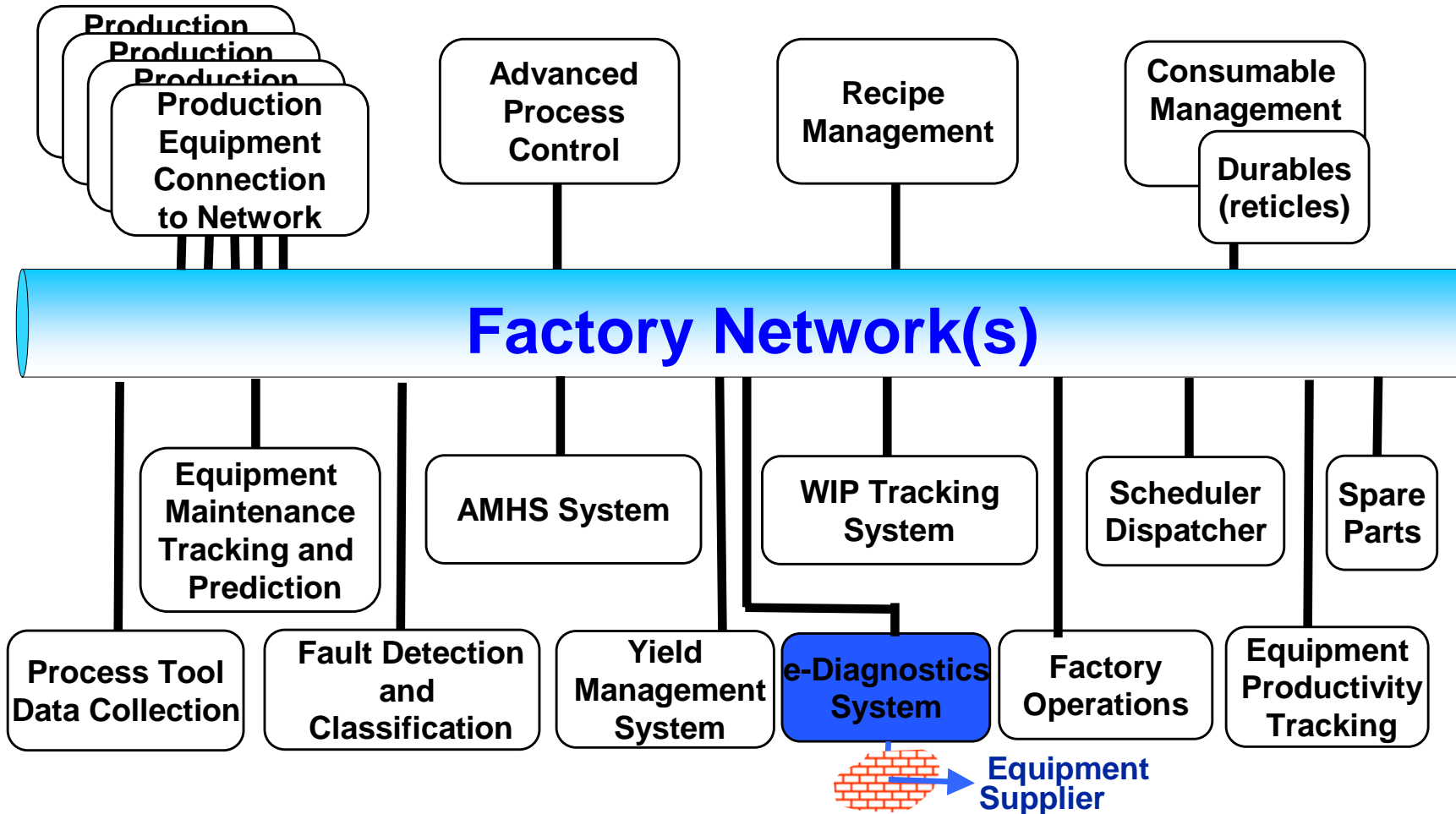
# e-Diagnostics Summary

- **300mm Standards implementation cannot be compromised by this effort!!**
- **e-Diagnostics is an outstanding ISMT example of IC makers and suppliers working together on a win-win initiative**
  - e-Diagnostic guidelines and capability definitions developed in H2'00
  - For the industry to reap the benefits, we must adhere to the Guidelines
  - e-Diagnostics solutions should follow these Guidelines
- **ISMT and SELETE/JEITA are collaborating on an Equipment Engineering Capabilities (EEC) concept**
  - Produced a set of global system guidelines for the e-Diagnostic capability
  - e-Diagnostic solutions should follow these guidelines
  - Future collaboration will expand the guidelines into e-Manufacturing

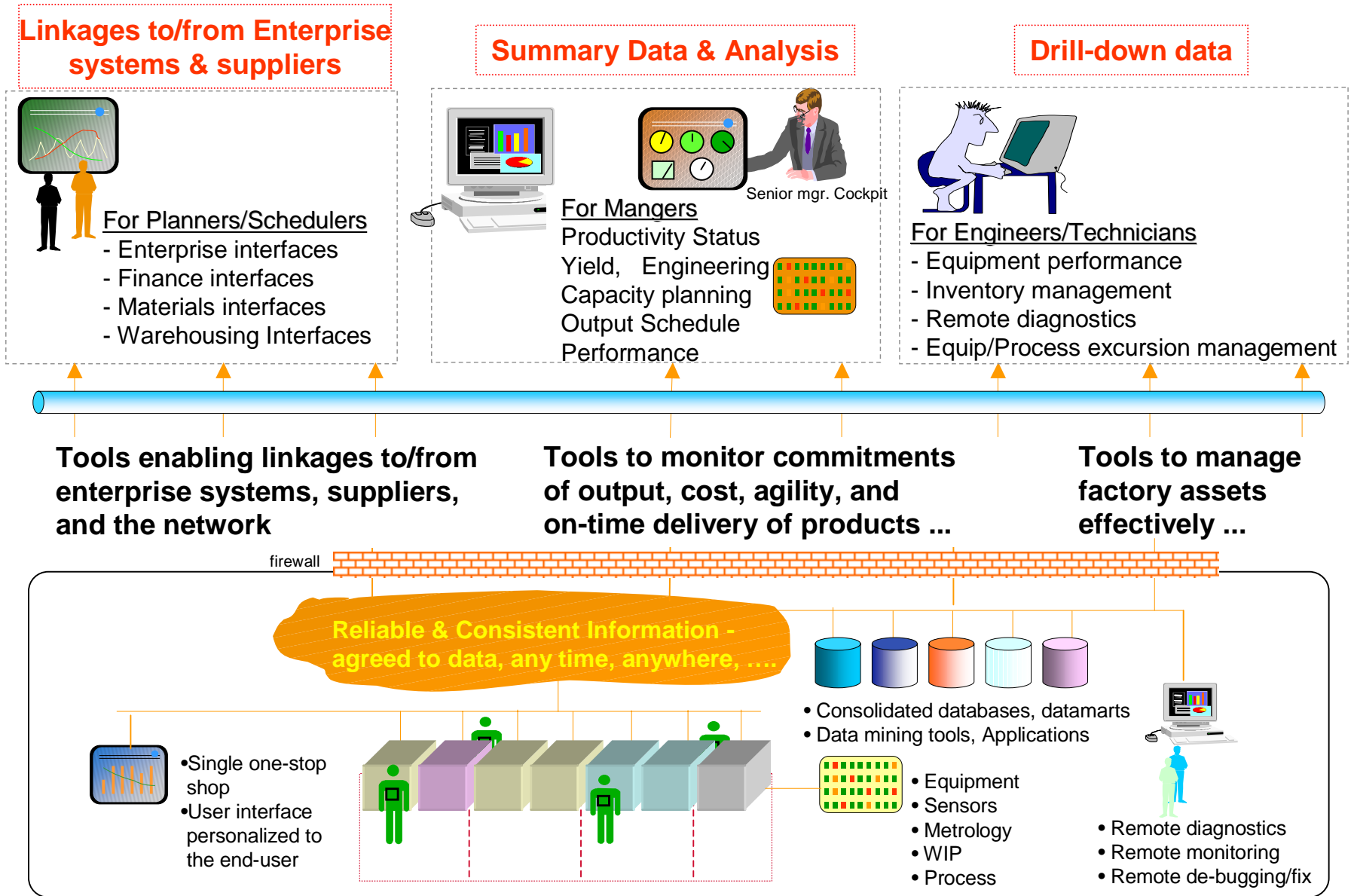
# Path to e-Factory - ISMT



# OEE Improvement through Global Factory Information System Guidelines



# An e-Manufacturing Vision



# e-Manufacturing Next Steps

- **Refine roadmaps**
- **Finalize Assessment checklists and deploy**
- **Prototype solutions to verify guidelines**
- **Transition guidelines (requirements) to standards**
- **Continue e-Manufacturing global collaboration**
  - Workshop - Austin, Oct. 19, e-Diagnostics, equipment ramp-up and maintenance support
  - Workshop - Tokyo, Dec., e-Diagnostics, APC, Recipe Download and Parameterization

**Thanks for your engagement and support!!**